

**Search Notes**

Application/Control No.

10/634,481

Examiner

James D. Stein

Applicant(s)/Patent under  
Reexamination

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Art Unit

2874

**SEARCHED**

Class	Subclass	Date	Examiner
385	15, 16, 27	5/23/2005	JDS

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
files	removed	5/23/2005	JDS

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See attached updated EAST search history	5/23/2005	JDS
IEEE and INSPEC: optical, delay, continuous, fixed, variable, discrete,	5/23/2005	JDS